Multifunctional Scanning Probe Microscope

A combination of AFM and micromechanical tester

Motorized XY micropositioning stage

Integrated top-view videosystem

A replaceable microtribometer / adhesiometer unit*

A replaceable shear-force microtribometer unit*

A replaceable nanoinden-tation/nanoscratching unit*

A replaceable platform for sample heating*

* Options

A realization of concept of micro/nano laboratory for material science

NT-206 combines functions of traditional atomic force microscope and original micromechanical tester,

Open design of NT-206 allows easy switch between these features and addition of new ones.

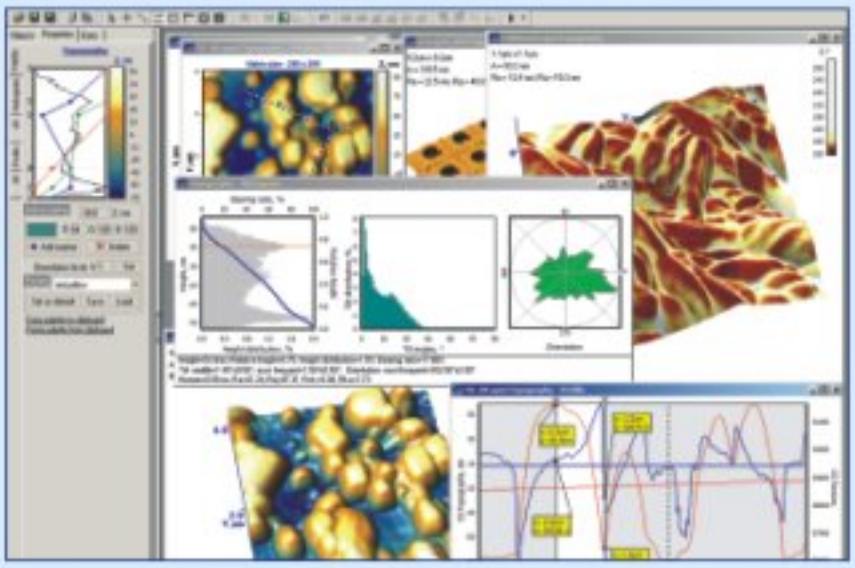
NT-206 unites functionality and quality in one instrument at reasonable price.

Fields of application:

- Solid-state physics
- Microelectronics
- Optics
- Thin-film technologies
- Nanotechnologies
- Semiconductor technologies
- Glasses and similartechnologies
- Micro- and nanotribology
- Smooth surface analysis
- Polymers and polymer-based composites
- High-precision mechanics
- Biological cells, membranes and other objects, etc.

NT-206 can be used in research and industrial laboratories, as well as for educational purposes in high schools.

Original techniques and recommendations on operation and methods are provide by specialists of A. V. Lykov Heat and Mass Transfer Institute of NASB.



Full-functionality Windows-based software for the instrument control and data processing and analysis with set of standard and unique functions.

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